

**Notice of References Cited**

Application/Control No.

10/626,610

Applicant(s)/Patent Under  
Reexamination  
ASANO ET AL.

Examiner

Matthew B. Smithers

Art Unit

2137

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*	C	US-6,952,486	10-2005	Yamakage et al.	382/100
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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